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... Therefore, it has a **high** accuracy only for a few number of filaments ... be stamped in the MNA matrix with the correct **dc** information in both **frequency** and time ...

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Hall, S. H.; Hall, G. W.; McCall, J. A.;

August 2000 Page(s):362

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3	BRS	L3	1036	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (threshold\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
4	BRS	L4	1	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (threshold\$) and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
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6	BRS	L6	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
7	BRS	L7	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
8	BRS	L8	4	(simulation same substrates) and (thresholds same integration) and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18

	Type	L #	Hits	Search Text	DBs	Time Stamp
9	BRS	L9	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wires\$	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
10	BRS	L10	2	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:19
11	BRS	L11	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$ and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:22
12	BRS	L12	2	"6925430".pn.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
13	BRS	L14	0	(substrate and (simulation or model) and (high adj frequency)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
14	BRS	L13	224	(substrate and (simulation or model)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28
15	BRS	L15	100	(substrate and (simulation)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28
16	BRS	L16	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28

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27	BRS	L27	11	(first adj threshold) and (second adj threshold) and wiring and circuits and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:41
28	BRS	L28	0	(first adj threshold) and (second adj threshold) and wiring and (skin adj resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
29	BRS	L29	0	(first adj threshold) and (second adj threshold) and wiring and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
30	BRS	L30	308	(first adj threshold) and (second adj threshold) and wiring and (resistance\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
31	BRS	L31	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and calulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
32	BRS	L32	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43

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33	BRS	L33	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43
34	BRS	L34	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
35	BRS	L35	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and elementsa	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
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38	BRS	L38	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and (elements near plurality) and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:47
39	BRS	L39	15	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:01
40	BRS	L40	4	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$) and simulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:12

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43	BRS	L43	2	716/5.ccls. and (first adj threshold) and (second adj threshold) and resistance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
44	BRS	L44	0	716/5.ccls. and (DC adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
45	BRS	L45	0	716/5.ccls. and (skin adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16
46	BRS	L46	11	716/5.ccls. and ((move or sort or arrange) same resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16

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